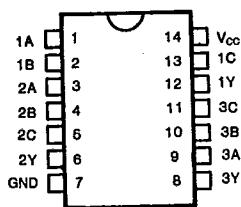


**KS54AHCT 10  
KS74AHCT****Triple 3-Input NAND Gates****FEATURES**

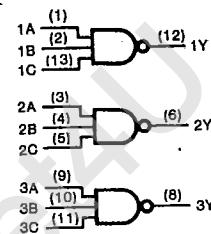
- Function, pin-out, speed and drive compatibility with 54/74ALS logic family
- Low power consumption characteristic of CMOS
- High-Drive Current outputs:  
 $I_{OL} = 8 \text{ mA} @ V_{OL} = 0.5\text{V}$
- Inputs and outputs interface directly with TTL, NMOS and CMOS devices
- Wide operating voltage range: 4.5V to 5.5V
- Characterized for operation over industrial and military temperature ranges:  
KS74AHCT:  $-40^{\circ}\text{C}$  to  $+85^{\circ}\text{C}$   
KS54AHCT:  $-55^{\circ}\text{C}$  to  $+125^{\circ}\text{C}$
- Package options include plastic "small outline" packages, standard plastic and ceramic 300-mil DIPs

**PIN CONFIGURATION****DESCRIPTION**

These devices contain three independent 3-input NAND gates. They perform the Boolean functions  $Y = \bar{A} \cdot \bar{B} \cdot \bar{C}$  or  $Y = \bar{A} + \bar{B} + \bar{C}$ .

These devices provide speeds and drive capability equivalent to their ALSTTL counterparts and yet maintain CMOS power levels. The input and output voltage levels allow direct interface with TTL, NMOS and CMOS devices without any external components.

All inputs and outputs are protected from damage due to static discharge by internal diode clamps to V<sub>CC</sub> and ground.

**LOGIC DIAGRAM****FUNCTION TABLE**

(Each Gate)

Inputs			Output
A	B	C	Y
H	H	H	L
L	X	X	H
X	L	X	H
X	X	L	H



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**KS54AHCT 10  
KS74AHCT****Triple 3-Input NAND Gates****Absolute Maximum Ratings\***

Supply Voltage Range V <sub>CC</sub> , . . . . .	-0.5V to +7V
DC Input Diode Current, I <sub>IK</sub> (V <sub>I</sub> < -0.5V or V <sub>I</sub> > V <sub>CC</sub> +0.5V) . . . . .	±20 mA
DC Output Diode Current, I <sub>OK</sub> (V <sub>O</sub> < -0.5V or V <sub>O</sub> > V <sub>CC</sub> +0.5V) . . . . .	±20 mA
Continuous Output Current Per Pin, I <sub>O</sub> (-0.5V < V <sub>O</sub> < V <sub>CC</sub> +0.5V) . . . . .	±35 mA
Continuous Current Through V <sub>CC</sub> or GND pins . . . . .	±125 mA
Storage Temperature Range, T <sub>STG</sub> . . . . .	-65°C to +150°C
Power Dissipation Per Package, P <sub>D</sub> . . . . .	500 mW

† Power Dissipation temperature derating:  
 Plastic Package (N): -12mW/°C from 65°C to 85°C  
 Ceramic Package (J): -12mW/°C from 100°C to 125°C

**Recommended Operating Conditions**

Supply Voltage, V <sub>CC</sub> . . . . .	4.5V to 5.5V
DC Input & Output Voltages*, V <sub>IN</sub> , V <sub>OUT</sub> . . . . .	0V to V <sub>CC</sub>
Operating Temperature	
Range	KS74AHCT: -40°C to +85°C KS54AHCT: -55°C to +125°C
Input Rise & Fall Times, t <sub>r</sub> , t <sub>f</sub> . . . . .	Max 500 ns

\* Unused inputs must always be tied to an appropriate logic voltage level (either V<sub>CC</sub> or GND)

**DC ELECTRICAL CHARACTERISTICS** (V<sub>CC</sub>=5V±10% Unless Otherwise Specified)

Characteristic	Symbol	Test Conditions	T <sub>a</sub> = 25°C	KS74AHCT		KS54AHCT		Unit
			Typ	T <sub>a</sub> = -40°C to +85°C	T <sub>a</sub> = -55°C to +125°C			
Minimum High-Level Input Voltage	V <sub>IH</sub>			2.0	2.0	2.0	2.0	V
Maximum Low-Level Input Voltage	V <sub>IL</sub>			0.8	0.8	0.8	0.8	V
Minimum High-Level Output Voltage	V <sub>OH</sub>	V <sub>IN</sub> =V <sub>IH</sub> or V <sub>IL</sub> I <sub>O</sub> =-20μA I <sub>O</sub> =-4mA	V <sub>CC</sub> 4.2	V <sub>CC</sub> -0.1 3.98	V <sub>CC</sub> -0.1 3.84	V <sub>CC</sub> -0.1 3.7	V <sub>CC</sub> -0.1 3.7	V
Maximum Low-Level Output Voltage	V <sub>OL</sub>	V <sub>IN</sub> =V <sub>IH</sub> or V <sub>IL</sub> I <sub>O</sub> =20μA I <sub>O</sub> =4mA I <sub>O</sub> =8mA	0	0.1 0.26 0.39	0.1 0.33 0.5	0.1 0.4	0.1 0.4	V
Maximum Input Current	I <sub>IN</sub>	V <sub>IN</sub> =V <sub>CC</sub> or GND		±0.1	±1.0	±1.0	±1.0	μA
Maximum Quiescent Supply Current	I <sub>CC</sub>	V <sub>IN</sub> =V <sub>CC</sub> or GND I <sub>OUT</sub> =0μA		2.0	20.0	40.0	40.0	μA
Additional Worst Case Supply Current	ΔI <sub>CC</sub>	per input pin V <sub>I</sub> =2.4V other Inputs: at V <sub>CC</sub> or GND I <sub>OUT</sub> =0μA		2.7	2.9	3.0	3.0	mA

**AC ELECTRICAL CHARACTERISTICS** (Input tr, tf≤2 ns), AHCT10

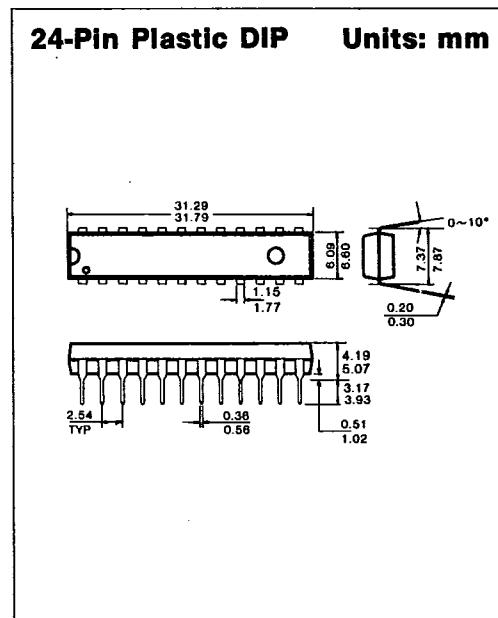
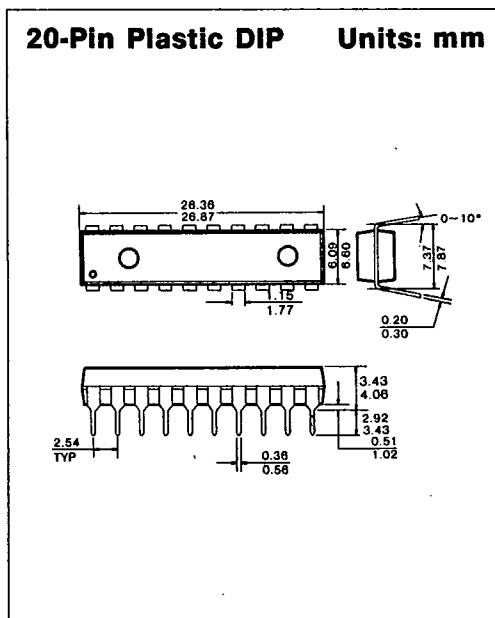
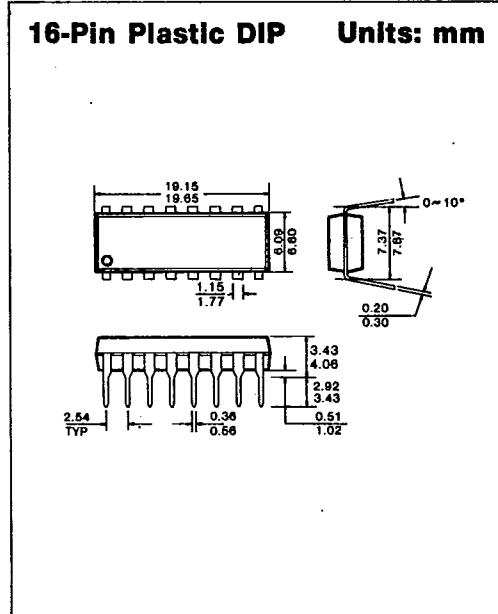
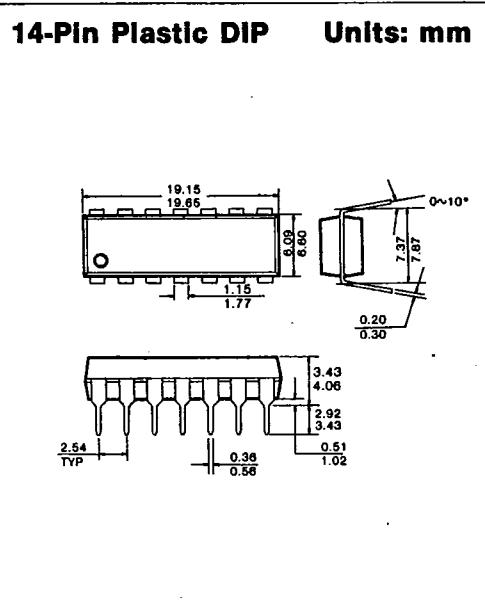
Characteristic	Symbol	Conditions <sup>†</sup>	T <sub>a</sub> = 25°C	KS74AHCT		KS54AHCT		Unit
			V <sub>CC</sub> = 5.0V	T <sub>a</sub> = -40°C to +85°C	V <sub>CC</sub> = 5.0V ± 10%	T <sub>a</sub> = -55°C to +125°C	V <sub>CC</sub> = 5.0V ± 10%	
Propagation Delay	t <sub>PLH</sub>	C <sub>L</sub> =50pF	9		15		18	ns
	t <sub>PHL</sub>		9		15		18	
Input Capacitance	C <sub>IN</sub>		5					pF
Power Dissipation Capacitance*	C <sub>PD</sub>	(per gate)	15					pF

\* C<sub>PD</sub> determines the no-load dynamic power dissipation: P<sub>D</sub>=C<sub>PD</sub> V<sub>CC</sub><sup>2</sup> f + I<sub>CC</sub> V<sub>CC</sub>.

† For AC switching test circuits and timing waveforms see section 2.



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**PACKAGE DIMENSIONS**T-90-20**1. PLASTIC PACKAGES**

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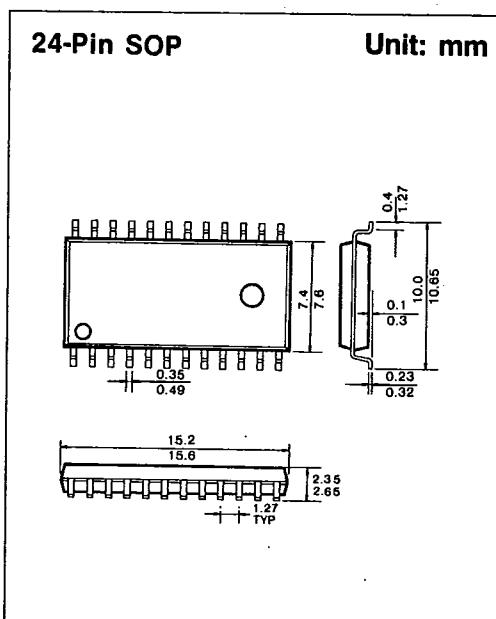
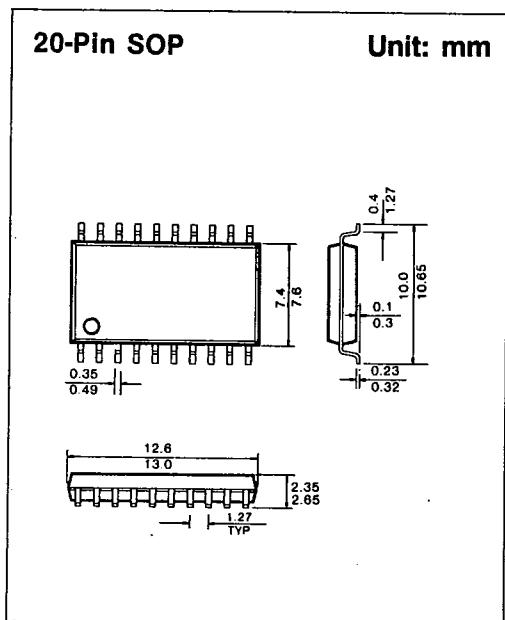
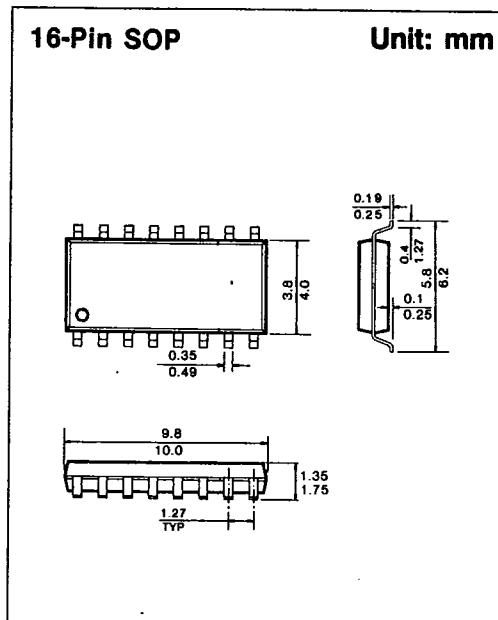
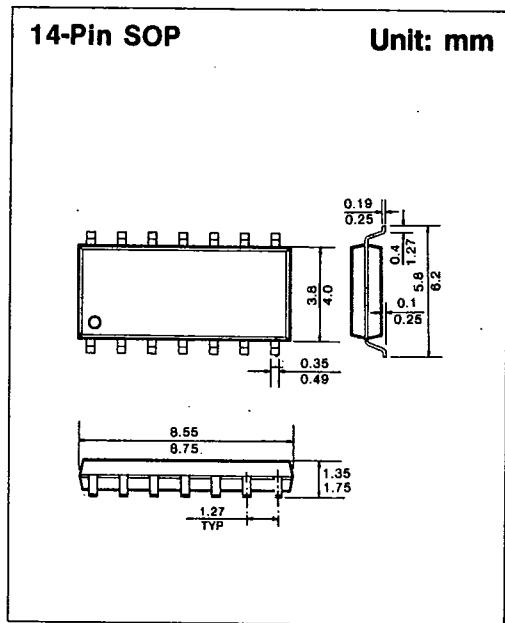


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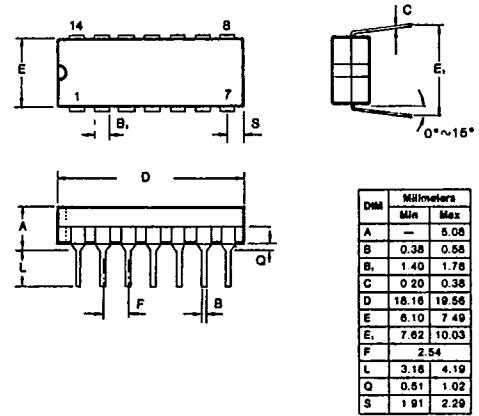
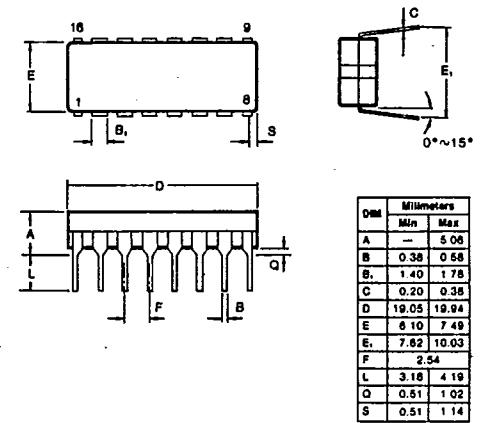
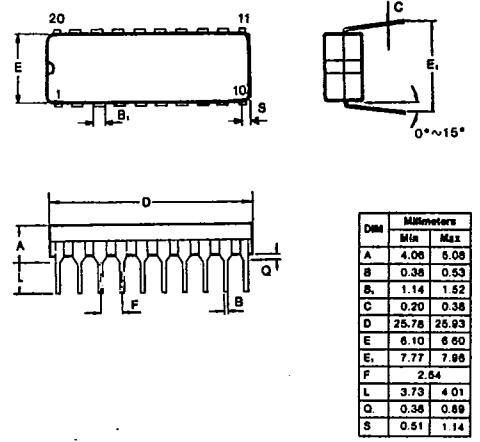
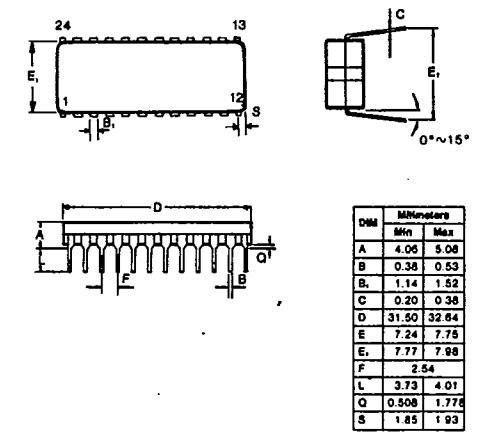
**PACKAGE DIMENSIONS****T-90-20**

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**PACKAGE DIMENSIONS**T-90-20**2. CERAMIC PACKAGES****14-Pin Ceramic DIP Units: mm****16-Pin Ceramic DIP Units: mm****20-Pin Ceramic DIP Units: mm****24-Pin Ceramic DIP Units: mm**

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